ABTS-P™

Advanced Burn-In & Test System
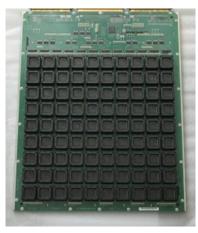
A high capacity system for test and burn-in of logic devices

System Benefits:

- True Per-pin Tester Architecture
    - 128 independent I/O channels per burn-in board
    - Per-pin voltage, timing, formatting and tri-state on-the-fly
    - 10MHz data rate, 20MHz clocks
- Very High System Capacity
    - Up to 72 burn-in board slots
    - Up to 36 pattern zones to handle small lots
    - 15KW chamber dissipation
    - Small system footprint
    - No side access required
- Low Cost of Ownership
    - Cost Effective Burn-in Boards (only edge fingers, no costly connectors, cost effective size)
    - Highly efficient power delivery
    - Low-power standby mode

ABTS

Burn in Board

"Setting the Test Standard for Tomorrow"

QUALITY SYSTEM CERTIFICATION
DNV·GL
ISO 9001

AEHR TEST SYSTEMS